

Description

The present invention relates to TTL to CMOS input buffers.

For many applications, it is desirable to provide a circuit which is capable of interfacing between transistor-transistor logic (TTL) levels and complementary MOS (CMOS) logic levels. In particular, TTL logic levels are nominally +2.4V for a logic "1" and 0.4V for a logic "0", and the associated CMOS levels are nominally +5.0V and 0.0V. The conventional interface circuit, also referred to in the art as an "input buffer circuit", comprises a p-channel MOS transistor and an n-channel MOS transistor connected in series between a positive power supply VDD (usually 5V) and ground. The gates of the devices are connected together and responsive to the TTL input signal. The drains of the transistors are also connected together and provide the CMOS output signal. In the ideal situation, one transistor of the pair will always be "off", preventing any current to flow through the pair of transistors from VDD to ground. However, this is not always the case. In particular, problems arise at the TTL input level for a logic "1", 2.4V, and when the TTL input level for a logic "0" is somewhat greater than 0.4V, for example, 0.8V. At these levels, both transistors may be "on" and a current will flow through the transistor pair to ground.

One solution is disclosed in U.S. Patent 4,471,242. The current flow through the devices is eliminated in this arrangement by introducing a reference voltage to match the lowest level of a logic "1" of the TTL input signal. This reference voltage is utilized in place of VDD as the supply voltage to the p-channel transistor, thus preventing the p-channel transistor from turning "on" when its gate voltage is at the lowest TTL logic "1" input level. A problem with this arrangement, however, is that by reducing the supply voltage of the p-channel transistor, the operating range of the buffer circuit is also restricted. By lowering the voltage available to operate the transistors, therefore, the device will be inherently slower. For many applications, this is not acceptable.

As an alternative solution, the actual sizes of the p- and n-channel transistors may be modified to prevent the static current flow. However, this solution is not practical since it requires additional masking levels and, therefore, additional processing time. Further, it is difficult with this method to accurately control the device sizes so as to reproducibly provide the necessary threshold voltage.

U.S.A. Patent No. 1,406,957 discloses a TTL to CMOS buffer which provides a level-shifted to the gate of a p-channel device in an input inverter during a low "logic one" signal of approximately 2.4V. This level shifted signal, which comprises the sum of the actual input signal (i.e. 2.4V) plus a number of level shifting diode voltage drops (each being approximately 0.8V), is

designed such that the p-channel device is turned "off", or at most, appears as a high impedance source during low "logic one" signals.

Therefore a need remains in the prior art for a TTL to CMOS input buffer which draws no static current, does not require additional processing steps, and is capable of operating over the entire 0—5V CMOS power supply level.

According to this invention there is provided a TTL to CMOS input buffer as claimed in claim 1.

The invention will now be described by way of example with reference to the accompanying drawings, in which:

Fig. 1 illustrates a simple prior art CMOS inverter which may be utilized to shift TTL logic level input signals to CMOS logic level output signals;

Fig. 2 is a graph illustrating the voltage transfer function, as well as static current flow, for the device illustrated in Fig. 1; and

Fig. 3 illustrates an exemplary TTL to CMOS input buffer without static current flow embodying the invention.

A prior art CMOS input buffer 10 is illustrated in Fig. 1. Input buffer 10 includes a p-channel MOS transistor 12 and an n-channel MOS transistor 14 connected in series between a positive power supply (denoted VDD) and a negative power supply, generally, ground. The gates of transistors 12 and 14 are connected together and receive as an input signal V_{IN} , the TTL input logic signal. Similarly, the drains of transistors 12 and 14 are connected together and provide the CMOS logic output signal, here denoted V_{OUT} . As shown in Fig. 1, a logic "0" to a logic "1" transition in TTL relates to a step change in voltage from approximately 0.4V to approximately 2.4V. In operation, when the input signal is at the logic "0" value, p-channel transistor 12 will be turned "on" and n-channel transistor 14 will be turned "off". Therefore, the voltage at node 0 will be approximately the positive supply voltage VDD, where VDD is typically 5V. When the TTL input signal is a logic "1", transistor 12 will be turned less "on", transistor 14 turned "on", and the voltage at node 0 will drop to near 0V, or ground. Fig. 2 illustrates (continuous line curve) the transfer function (V_{OUT} vs V_{IN}) of the circuit illustrated in Fig. 1. When V_{IN} is equal to 0V V_{OUT} will be at its maximum potential of VDD, or 5V. As V_{IN} approaches 1.6V, both transistors 12 and 14 will be turned "on", and V_{OUT} will switch from VDD to ground. As can be seen by reference to Fig. 2, the switch is not instantaneous, and there exists a predetermined voltage interval wherein V_{IN} provides a sufficient gate voltage to both transistors so as to override their respective threshold voltages. This is the interval wherein static current i_d (dashed line curve) will flow from VDD through transistors 12 and 14 to ground. As stated above, it is necessary in many applications to reduce, or even better, eliminate, this current flow. To achieve this, therefore, it is necessary to ensure that both transistors forming the CMOS inverter are never in conduction at the

same time.

Shown in Fig. 3 is a TTL to CMOS input buffer embodying the invention which eliminates the static current flow through the p-channel and n-channel transistors. Input buffer comprises a first CMOS inverter 30, a second CMOS inverter 38, a transition detector 44, and a voltage boosting circuit 50. The TTL logic input signal V_{IN} is applied as an input to the first CMOS inverter 30 via an n-channel transistor 22, where the source of transistor 22 is connected to receive input signal V_{IN} . The gate of transistor 22 is controlled by a reference voltage V_{ref} , later described, and the drain of transistor 22 is connected to the input of first CMOS inverter 30, where this connection is illustrated as node A in Fig. 3. First CMOS inverter 30 comprises, as shown in Fig. 3 a p-channel transistor 32 and an n-channel transistor 34 connected in series between the positive power supply VDD and ground. The gates of transistors 32 and 34 are coupled together and connected to the drain of transistor 22 at node A. The drains of transistors 32 and 34 are also coupled together and provide the output of first inverter 30 at node B, where this output signal is defined as V_{OUT1} . Output signal V_{OUT1} is provided at essentially VDD when input signal V_{IN} is logic "0" and at essentially ground when input signal V_{IN} is a logic "1".

The output of first CMOS inverter 30 is subsequently applied as an input to second CMOS inverter 38. Second CMOS inverter 38 is similar in structure to first CMOS inverter 30 and comprises a p-channel transistor 40 and an n-channel transistor 42 connected between VDD and ground. The output of second CMOS inverter 38, denoted V_{OUT2} , will be the opposite of the output from first CMOS inverter 30. The combination of the two inverters 30 and 38 is a known TTL to CMOS buffer. It operates as follows.

When input signal V_{IN} is a logic "1", transistor 22 must be "off". Therefore, the reference voltage V_{ref} is chosen to ensure that transistor 22 will remain "off" when the TTL input signal is at its lowest logic "1" value of approximately 2V. Thus, the input to first inverter 30 at node A will be approximately 1.8V, including some noise margin. One of the advantages of utilizing transistor 22 is that the input inverter transistors 32 and 34 do not have to be ratioed to accept TTL input levels, since device 22 enables node A to go fully to VCC. This logic "1" value turns "on" n-channel transistor 34 and turns "off" p-channel transistor 32, pulling the voltage appearing at node B, V_{OUT1} , to ground. Consequently, this logic "0" value of V_{OUT1} is applied as the input to second inverter 38, turning p-channel transistor 40 "on" and n-channel transistor 42 "off" and bringing the value of output signal V_{OUT2} to essentially VDD, or logic "1". In summary, therefore, when the TTL input signal V_{IN} is a logic "1", V_{OUT1} will be a logic "0" and V_{OUT2} will be a logic "1", where the actual values of V_{OUT1} and V_{OUT2} will be the CMOS voltage levels of ground (0V) and VDD (5V), respectively. Similarly, when input signal V_{IN} is a logic "0", transistor 32 of first inverter 30 will turn

"on" and transistor 34 will turn "off", thus bringing the voltage at node B up from ground to essentially VDD, the CMOS logic "1" level. In turn, this logic "1" input to second inverter 38 will turn transistor 40 "off" and transistor 42 "on", bringing the output of second inverter 38 down from VDD to ground, the CMOS logic "0" level.

As briefly stated above in association with Fig. 1, a problem arises when the TTL input signal V_{IN} is at its lowest logic "1" value of 2V. Under this condition, both transistors 32 and 34 will be "on" and will draw a current from VDD to ground. Under some circumstances, this current may reach a value of 3A, which is not acceptable for many situations. To avoid this situation, therefore, it is necessary to bring the TTL logic "1" input voltage of 2V appearing at node A up to a level which is sufficient to ensure that p-channel transistor 32 will be completely turned "off". A solution is provided by including the transition detector 44 and the voltage boosting circuit 50 in the input buffer.

Transition detector 44 comprises a p-channel transistor 46 and an n-channel transistor 48. The source of transistor 46 is connected to VDD, the drain is connected to the drain of transistor 48, and the gate is coupled to receive the output signal V_{OUT2} from second inverter 38. The source of transistor 48 is connected to ground and the gate of transistor 48 is coupled to receive the TTL input signal V_{IN} . The output of transition detector 44, denoted V_{TRANS} , will appear at node D, the interconnected drain terminals of transistors 46 and 48. Voltage boosting circuit 50, as shown in Fig. 3, comprises a pair of p-channel transistors 52 and 54 connected in series between VDD and node A, the input to first inverter 30. In particular, the source of transistor 52 is connected to VDD, the drain of transistor 52 is connected to the source of transistor 54, and the drain of transistor 54 is connected to node A. The gate of transistor 52 is controlled by output signal V_{OUT2} from second inverter 38 and the gate of transistor 54 is controlled by output signal V_{TRANS} from transition detector 44. A delay element 56 is included in boosting circuit 50, the purpose of this device being explained below.

As previously discussed, conventional TTL to CMOS input buffers will draw a static current I_d when the TTL input signal makes a logic "0" to a logic "1" transition, where the logic "1" signal is of insufficient magnitude to turn "off" the p-channel transistor of the CMOS inverter. In the operation of the present embodiment, when V_{IN} moves from a logic "0" to a logic "1" value, transistor 48 of transition detector 44 will turn "on", bringing the output V_{TRANS} of detector 44 to ground. This CMOS logic "0" value of V_{TRANS} is subsequently applied as the gate input of p-channel transistor 54, turning "on" transistor 54. At this point in time, the signal appearing at the gate of p-channel transistor 52 will also be at ground, since the TTL input transition from logic "0" to logic "1" has not yet propagated through delay element 56. Therefore, once transistor 54 is

activated, node A will be brought up from the TTL logic "1" value of approximately 2V towards the full VDD CMOS logic "1" level. Thus, with node A sufficiently above the threshold of p-channel transistor 32, transistor 32 will remain "off" and no current will flow through first inverter 30. As can be seen from the above description, delay element 56 (which may simply comprise a pair of CMOS inverters) functions to ensure that transistor 52 will not be turned "off" (by the transition of V_{OUT2} from "0" to "1" in association with the identical transition of input signal V_{IN}) until transistor 54 has been "on" long enough to bring the voltage at node A to a level which will turn transistor 32 "off". It has been determined that a delay of approximately 10—15 nsec is sufficient for this purpose.

Once the logic "1" value of V_{OUT2} has propagated through delay element 56 and reaches the gate of transistor 52, transistor 52 will be turned "off", thereby disconnecting node A from VDD. Transistor 52 is turned "off" so that when input signal V_{IN} makes its next transition from logic "1" to logic "0", node A is not actively held at VDD, where that condition would draw current from the TTL input source, which is not desirable. Also, it would considerably slow down the "1" to "0" transition time and thus decrease the operating speed of input buffer 20.

A problem may be encountered when the input signal V_{IN} remains at a logic "1" value for a considerable length of time. Under these circumstances, the voltage at node A may decay to a level which would allow p-channel transistor 32 to turn "on" and static current to flow through inverter 30. To alleviate this problem, a p-channel leakage transistor 60 may be included in first inverter 30 of input buffer 20 as shown in Fig. 3. Leakage transistor 60 is connected at its source to VDD, and the drain of transistor 60 is connected to node A. The gate of transistor 60 is connected to node B, thus transistor 60 will turn "on" when output signal V_{OUT1} is at a logic "0" value. By design, transistor 60 is made to be extremely small, and will therefore not interfere with the operation of voltage boosting circuit 50. However, after transistor 52 has been "off" for a given length of time, transistor 60 will provide a path for leakage current so that static current will not flow from VDD through transistors 32 and 34 to ground. Due to its extremely small size, the current flow through leakage transistor 60 is considered negligible.

Claims

1. A TTL to CMOS input buffer for receiving an input signal having first ("0") and second ("1") logic states at the associated TTL voltage levels, and for providing an output logic signal corresponding thereto at the associated CMOS voltage levels, comprising a first CMOS inverter (30) responsive to the TTL input logic signal for providing as an output a first CMOS logic signal of opposite logic state, a second CMOS inverter (38)

responsive to the first CMOS logic signal for providing as an output a second CMOS logic signal of like logic state as the TTL input logic signal, a transition detector responsive to the TTL input logic signal, and voltage boosting means for providing an increased voltage signal at the input to the first CMOS inverter when the TTL input logic signal changes from the first logic state to the second logic state, and characterised in that the transition detector (44) comprises a plurality of transistors responsive to both the TTL input logic signal and the second CMOS logic signal for generating as an output a transition output control signal, and the voltage boosting means (50) comprises a plurality of transistors responsive to both the second CMOS logic signal and the transition output control signal for providing a conduction path between a power supply voltage point and the first CMOS inverter.

2. An input buffer as claimed in claim 1 wherein the transition detector comprises a first transistor (46) of a first conductivity type having a first current electrode coupled to a first power supply point, a second current electrode for providing the transition output control signal, and a gate electrode for receiving as an input the second CMOS logic signal, and a second transistor (48) of a second conductivity type having a first current electrode coupled to a second power supply point, a second current electrode coupled to the second current electrode of the first transistor, and a gate electrode for receiving as an input the TTL input logic signal.

3. An input buffer as claimed in claim 1 or 2 wherein the voltage boosting means comprises delay means (56) responsive to the second CMOS logic signal for producing as an output a delayed second CMOS logic signal, a first transistor (52) of a first conductivity type having a first current electrode coupled to a first power supply point, a second current electrode, and a gate electrode responsive to the delayed second CMOS logic signal, and a second transistor (54) of the first conductivity type having a first current electrode coupled to the second current electrode of the first transistor, a second current electrode coupled to the input of the first CMOS inverter, and a gate electrode responsive to the transition output control signal.

Patentansprüche

1. TTL-CMOS-Eingangspuffer zur Aufnahme eines Eingangssignals, das einen ersten ("0") und einen zweiten ("1") Logikzustand mit den zugeordneten TTL-Spannungspegeln besitzt, und zur Lieferung eines entsprechenden Ausgangslogiksignals mit den zugeordneten CMOS-Spannungspegeln, mit einem ersten CMOS-Inverter (30), der unter Ansprechen auf das TTL-Eingangslogiksignal als Ausgangssignal ein erstes CMOS-Logiksignal mit entgegengesetztem Logikzustand liefert, einem zweiten CMOS-Inverter (38), der unter Ansprechen auf das erste CMOS-Logiksignal als Ausgangssignal ein zweites CMOS-Logiksignal

activated, node A will be brought up from the TTL logic "1" value of approximately 2V towards the full VDD CMOS logic "1" level. Thus, with node A sufficiently above the threshold of p-channel transistor 32, transistor 32 will remain "off" and no current will flow through first inverter 30. As can be seen from the above description, delay element 56 (which may simply comprise a pair of CMOS inverters) functions to ensure that transistor 52 will not be turned "off" (by the transition of V_{OUT2} from "0" to "1" in association with the identical transition of input signal V_{IN}) until transistor 54 has been "on" long enough to bring the voltage at node A to a level which will turn transistor 32 "off". It has been determined that a delay of approximately 10–15 nsec is sufficient for this purpose.

Once the logic "1" value of V_{OUT2} has propagated through delay element 56 and reaches the gate of transistor 52, transistor 52 will be turned "off", thereby disconnecting node A from VDD. Transistor 52 is turned "off" so that when input signal V_{IN} makes its next transition from logic "1" to logic "0", node A is not actively held at VDD, where that condition would draw current from the TTL input source, which is not desirable. Also, it would considerably slow down the "1" to "0" transition time and thus decrease the operating speed of input buffer 20.

A problem may be encountered when the input signal V_{IN} remains at a logic "1" value for a considerable length of time. Under these circumstances, the voltage at node A may decay to a level which would allow p-channel transistor 32 to turn "on" and static current to flow through inverter 30. To alleviate this problem, a p-channel leakage transistor 60 may be included in first inverter 30 of input buffer 20 as shown in Fig. 3. Leakage transistor 60 is connected at its source to VDD, and the drain of transistor 60 is connected to node A. The gate of transistor 60 is connected to node B, thus transistor 60 will turn "on" when output signal V_{OUT1} is at a logic "0" value. By design, transistor 60 is made to be extremely small, and will therefore not interfere with the operation of voltage boosting circuit 50. However, after transistor 52 has been "off" for a given length of time, transistor 60 will provide a path for leakage current so that static current will not flow from VDD through transistors 32 and 34 to ground. Due to its extremely small size, the current flow through leakage transistor 60 is considered negligible.

Claims

1. A TTL to CMOS input buffer for receiving an input signal having first ("0") and second ("1") logic states at the associated TTL voltage levels, and for providing an output logic signal corresponding thereto at the associated CMOS voltage levels, comprising a first CMOS inverter (30) responsive to the TTL input logic signal for providing as an output a first CMOS logic signal of opposite logic state, a second CMOS inverter (38)

responsive to the first CMOS logic signal for providing as an output a second CMOS logic signal of like logic state as the TTL input logic signal, a transition detector responsive to the TTL input logic signal, and voltage boosting means for providing an increased voltage signal at the input to the first CMOS inverter when the TTL input logic signal changes from the first logic state to the second logic state, and characterised in that the transition detector (44) comprises a plurality of transistors responsive to both the TTL input logic signal and the second CMOS logic signal for generating as an output a transition output control signal, and the voltage boosting means (50) comprises a plurality of transistors responsive to both the second CMOS logic signal and the transition output control signal for providing a conduction path between a power supply voltage point and the first CMOS inverter.

2. An input buffer as claimed in claim 1 wherein the transition detector comprises a first transistor (46) of a first conductivity type having a first current electrode coupled to a first power supply point, a second current electrode for providing the transition output control signal, and a gate electrode for receiving as an input the second CMOS logic signal, and a second transistor (48) of a second conductivity type having a first current electrode coupled to a second power supply point, a second current electrode coupled to the second current electrode of the first transistor, and a gate electrode for receiving as an input the TTL input logic signal.

3. An input buffer as claimed in claim 1 or 2 wherein the voltage boosting means comprises delay means (56) responsive to the second CMOS logic signal for producing as an output a delayed second CMOS logic signal, a first transistor (52) of a first conductivity type having a first current electrode coupled to a first power supply point, a second current electrode, and a gate electrode responsive to the delayed second CMOS logic signal, and a second transistor (54) of the first conductivity type having a first current electrode coupled to the second current electrode of the first transistor, a second current electrode coupled to the input of the first CMOS inverter, and a gate electrode responsive to the transition output control signal.

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1. TTL-CMOS-Eingangspuffer zur Aufnahme eines Eingangssignals, das einen ersten ("0") und einen zweiten ("1") Logikzustand mit den zugeordneten TTL-Spannungspegeln besitzt, und zur Lieferung eines entsprechenden Ausgangslogiksignals mit den zugeordneten CMOS-Spannungspegeln, mit einem ersten CMOS-Inverter (30), der unter Ansprechen auf das TTL-Eingangslogiksignal als Ausgangssignal ein erstes CMOS-Logiksignal mit entgegengesetztem Logikzustand liefert, einem zweiten CMOS-Inverter (38), der unter Ansprechen auf das erste CMOS-Logiksignal als Ausgangssignal ein zweites CMOS-Logiksignal



mit gleichem Logikzustand wie das TTL-Eingangsalogiksignal liefert, einem Flankendetektor, der auf das TTL-Eingangsalogiksignal anspricht, und eine Spannungsverstärkungseinrichtung zur Lieferung eines vergrößerten Spannungssignals am Eingang des ersten CMOS-Inverters, wenn das TTL-Eingangsalogiksignal vom ersten Logikzustand in den zweiten Logikzustand übergeht, dadurch gekennzeichnet, daß der Flankendetektor (44) eine Vielzahl von Transistoren aufweist, die unter Ansprechen sowohl auf das TTL-Eingangsalogiksignal als auch das zweite CMOS-Logiksignal als Ausgangssignal ein Flanken-Ausgangs-Steuersignal liefern und daß die Spannungsverstärkungseinrichtung (50) eine Vielzahl von Transistoren umfaßt, die unter Ansprechen sowohl auf das zweite CMOS-Logiksignal und das Flanken-Ausgangssteuersignal einen leitenden Weg zwischen einem Spannungsversorgungspunkt und dem ersten CMOS-Inverter bereitstellen.

2. Eingangspuffer nach Anspruch 1, bei dem der Flankendetektor einen ersten Transistor (46) eines ersten Leitfähigkeitstyps aufweist, der eine erste, mit einem ersten Spannungsversorgungspunkt verbundene stromführende Elektrode, eine zweite Stromführende Elektrode zur Lieferung des Flanken-Ausgangssteuersignals und eine Gate-Elektrode zur Aufnahme des zweiten CMOS-Logiksignals als Eingangssignal besitzt, sowie einen zweiten Transistor (48) eines zweiten Leitfähigkeitstyps aufweist, der eine erste, mit einem zweiten Spannungsversorgungspunkt verbundene stromführende Elektrode, eine zweite, mit der zweiten stromführenden Elektrode des ersten Transistors verbundene stromführende Elektrode und eine Gate-Elektrode zur Aufnahme des TTL-Eingangsalogiksignals als Eingangssignal besitzt.

3. Eingangspuffer nach Anspruch 1 oder 2, bei dem die Spannungsverstärkungseinrichtung ein Verzögerungseinrichtung (56) aufweist, die unter Ansprechen auf das zweite CMOS-Logiksignal als Ausgangssignal ein verzögertes zweites CMOS-Logiksignal liefert, ferner einen ersten Transistor (52) eines ersten Leitfähigkeitstyps aufweist, der eine erste, mit einem ersten Spannungsversorgungspunkt verbundene stromführende Elektrode, eine zweite stromführende Elektrode und eine Gate-Elektrode besitzt, die auf das verzögerte zweite CMOS-Logiksignal anspricht, und einen zweiten Transistor (54) des ersten Leitfähigkeitstyps aufweist, der eine erste, mit der zweiten stromführenden Elektrode des ersten Transistors verbundene stromführende Elektrode, eine zweite, mit dem Eingang des ersten CMOS-Inverters verbundene stromführende Elektrode und eine Gate-Elektrode besitzt, die auf das Flanken-Ausgangssteuersignal anspricht.

Revendications

1. Un amplificateur-séparateur d'entrée pour l'interface TTL-CMOS, destiné à recevoir un signal d'entrée ayant des premier ("0") et second ("1") états logiques aux niveaux de tension TTL asso-

ciés, et à fournir un signal logique de sortie correspondant, aux niveaux de tension CMOS associés, comprenant un premier inverseur CMOS (30) qui réagit au signal logique d'entrée TTL en fournissant à titre de signal de sortie un premier signal logique CMOS ayant l'état logique opposé, un second inverseur CMOS (38) qui réagit au premier signal logique CMOS en fournissant à titre de signal de sortie un second signal logique CMOS ayant le même état logique que le signal logique d'entrée TTL, un détecteur de transition qui réagit au signal logique d'entrée TTL, et des moyens d'augmentation de tension qui appliquent un signal de tension accrue à l'entrée du premier inverseur CMOS lorsque le signal logique d'entrée TTL passe du premier état logique au second état logique, et caractérise en ce que le détecteur de transition (44) comprend un ensemble de transistors qui réagissent à la fois au signal logique d'entrée TTL et au second signal logique CMOS en produisant à titre de signal de sortie un signal de commande de sortie de transition, et les moyens d'augmentation de tension (50) comprennent un ensemble de transistors réagissant à la fois au second signal logique CMOS et au signal de commande de sortie de transition en établissant un chemin de conduction entre un point de tension d'alimentation et le premier inverseur CMOS.

2. Un amplificateur-séparateur selon la revendication 1, dans lequel le détecteur de transition comprend un premier transistor (46) d'un premier type de conductivité et ayant une première électrode de courant connectée à un premier point d'alimentation, une seconde électrode de courant destinée à fournir le signal de commande de sortie de transition, et une électrode de grille destinée à recevoir à titre de signal d'entrée le second signal logique CMOS, et un second transistor (48) d'un second type de conductivité, ayant une première électrode de courant connectée à un second point d'alimentation, une seconde électrode de courant connectée à la seconde électrode de courant du premier transistor, et une électrode de grille destinée à recevoir à titre de signal d'entrée le signal logique d'entrée TTL.

3. Un amplificateur-séparateur selon la revendication 1 ou la revendication 2, dans lequel les moyens d'augmentation de tension comprennent des moyens de retard (56) qui réagissent au second signal logique CMOS en produisant à titre de signal de sortie un second signal logique CMOS retardé, un premier transistor (52) d'un premier type de conductivité, ayant une première électrode de courant connectée à un premier point d'alimentation, une seconde électrode de courant, et une électrode de grille qui réagit au second signal logique CMOS retardé, et un second transistor (54) du premier type de conductivité, ayant une première électrode de courant connectée à la seconde électrode de courant du premier transistor, une seconde électrode de courant connectée à l'entrée du premier inverseur CMOS, et une électrode de grille qui réagit au signal de commande de sortie de transition.

